



## Power Mixed Signal ASIC Library

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## Rationale/Challenges

- Reduce mass, volume and power
- Survive severe environments
  - Europa radiation environment
  - Life
- High reliability
  - Power cross-strap and current limiting on chip
- Low voltage process
  - Needed to develop high voltage transistors
  - High common mode transients





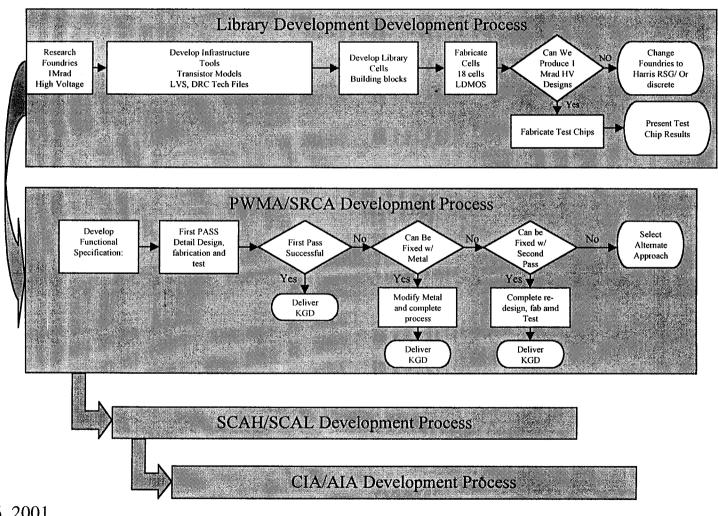
# Boeing/JPL Cell Development

- Identify Need for a Function
- Develop Preliminary Spec
- Design the Cell So That Simulation Results Predict Success
- Plan for Test/Design In Test Points and Structures
- Review by Peers
- Perform Layout
- Integrate with Other Cells
- Release to Foundry
- Prepare for Test
- Develop Behavioral Model
- Perform Testing to Verify Performance to Specifications, Including Rad
- Update Spec and Behavioral Model as Required
- Freeze the Design
- Store Parts for Use in Breadboards





# Power Mixed Signal ASIC Development Plan

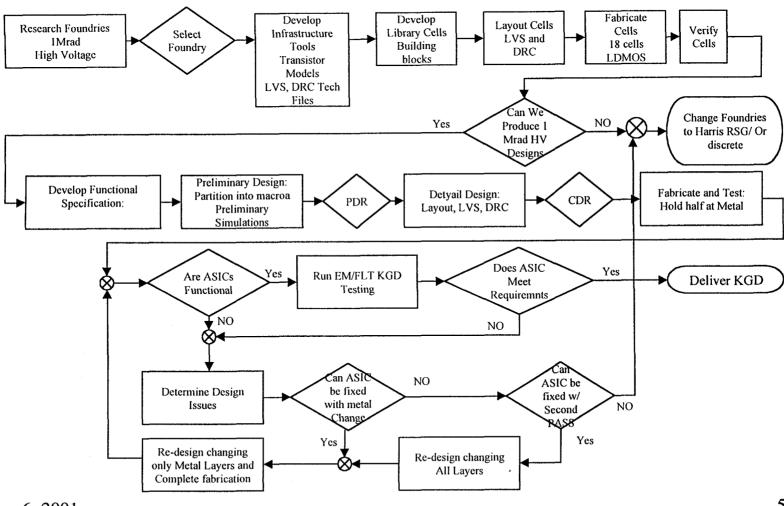


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# Mixed Signal ASIC Detail Design Flow



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#### Pulse Width Modulator (PWMA)

- High frequency switching regulator (1 Mhz)
- 2 A transient 1 Mhz CHFET driver

#### Synchronous Rectifier Controller SRCA

- High Speed Synchronous CHFET Driver
- High Voltage Linear Regulator

#### Switch Control ASIC High Side (SCAH)

- Floating High speed linear MOSFET control
- Low offset current sense

#### Switch Control ASIC Low Side (SCAL)

- Ground Referenced Power Switch Control
- Charge Pump, Level Shifting (40V)

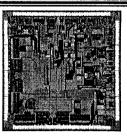
#### Command Interface ASIC (CIA)

- Microcontroller with imbedded RAM,ROM
- A-to-D Converter, Power Cross-strap

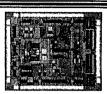
#### Analog Interface ASIC (AIA)

Isolated I2C Bus Interface

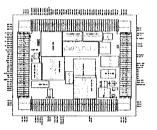
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PWMA HX2080



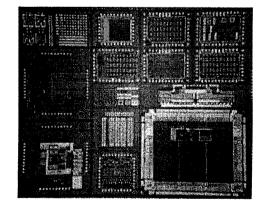
SRCA HX2040



SCAH Layout CDR: 6/28/01



SCAL Layout CDR: 6/28/01



A/D Test CHIP





#### Status

- Boeing completed fabrication and test of the initial library
- Completed fabrication of two test chips
  - Boeing Library
  - A/D Test Chip
- Completed fabrication of the PWMA and SRCA first pass
  - In test, verifying functionality (>90%)
  - POR timing issue, Auto-zero offset
- SCA CDR is planned for 6/28/01
  - PSPICE behavioral models are complete
- CIA CDR is planned for 10/22/01